Agenda Micro-XRF User School

Duration: 3 days
Location: Bruker Nano Analytics Headquarters, Bruker Nano GmbH, Am Studio 2D, 12489 Berlin-Adlershof

Day 1

9:00 a.m.	**Principles of Micro-XRF** Origin of X-ray fluorescence X-ray tubes and spectra X-ray optics Characteristic peaks: K-, L-, and M-series Moseley Compton/Rayleigh/Bragg X-ray detection Quantitative XRF/Sherman
10:30 a.m.	**General Hardware features and settings** Chamber Sources Filters Detectors Stage Cameras
11:00 a.m.	**General Software Features** Workspaces
11:30 a.m.	**Instrument Check “Quality Management”**
12:30-1:30 p.m.	**lunch break**
1:30 p.m.	**Working with Point and Multi-Point workspace** Sample placing Mosaic Images Selecting measurement positions Adapted measurement settings and time
2:30 p.m.	**Exercises (off line)** Element identification (Metals and Minerals)
3:30 p.m.	**Q&A session**

Day 2

9:00 a.m.	**Working with Line, Areas workspace**
10:00 a.m.	**Hands on Training (I) exercises with various samples on the M4 Tornado**
12:30-1:30 p.m.	**lunch break**
1:30 p.m.	**Training exercises with various samples instrument** **Point and Multipoint and Line scan** (qualitative, quantitative)
3:00 p.m.	**Analytical possibilities pitfalls and setting for complex samples**
3:30 p.m.	**Q&A session**

Day 3

9:00 a.m.	**Mapping, quantitative mapping and Hyper-Mapping** Applications of different Mapping modes, Maximum Pixel Spectrum, Automatic phase analysis
11:30 a.m.	**Hands on Training (I) with various samples on the M4 Tornado Mapping**
12:30-1:30 p.m.	**lunch break**
1:30 p.m.	**Q&A session and discussions of specific customer applications**
2:15 p.m.	**Hands on Training (III)**
3:30 p.m.	**Summary**

Hand out of certificates

Per request:	**Special functions**